

<b>Notice of References Cited</b>	Application/Control No. 10/723,326	Applicant(s)/Patent Under Reexamination SATKUNANATHAN ET AL.	
	Examiner Cristina Owen Sherr	Art Unit 3621	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,381,640	04-2002	Beck et al.	705/10
*	B	US-5,671,412	09-1997	Christiano, Matt	707/104.1
*	C	US-6,502,234	12-2002	Gauthier et al.	717/107
*	D	US-6,295,531	09-2001	Bae et al.	707/4
*	E	US-6,233,726	05-2001	Bowman et al.	707/102
*	F	US-6,053,951	04-2000	McDonald et al.	717/109
*	G	US-5,966,532	10-1999	McDonald et al.	707/101
*	H	US-5,859,637	01-1999	Tidwell, II, Leonard Douglas	715/708
*	I	US-6,564,375	05-2003	Jiang, Yansheng	707/103R
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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